# 2SB0956

# Silicon PNP epitaxial planar type

For low-frequency output amplification Complementary to 2SD1280

## ■ Features

- Large collector power dissipation P<sub>C</sub>
- Low collector-emitter saturation voltage V<sub>CE(sat)</sub>
- Mini Power type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing.

# ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	$V_{CBO}$	-20	V	
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	-20	V	
Emitter-base voltage (Collector open)	$V_{EBO}$	<b>-</b> 5	V	
Collector current	Ic	-1	A	
Peak collector current	$I_{CP}$	-2	A	
Collector power dissipation *	P <sub>C</sub>	1	W	
Junction temperature	$T_{j}$	150	°C	
Storage temperature	$T_{stg}$	-55 to +150	°C	

Note) \*: Print circuit board: Copper foil area of 1 cm<sup>2</sup> or more, and the board thickness of 1.7 mm for the collector portion

# Unit: mm 4.5±0.1 1.6±0.2 1.5±0.1 0.4±0.04 1.5±0.1 1

Marking Symbol: H

# ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

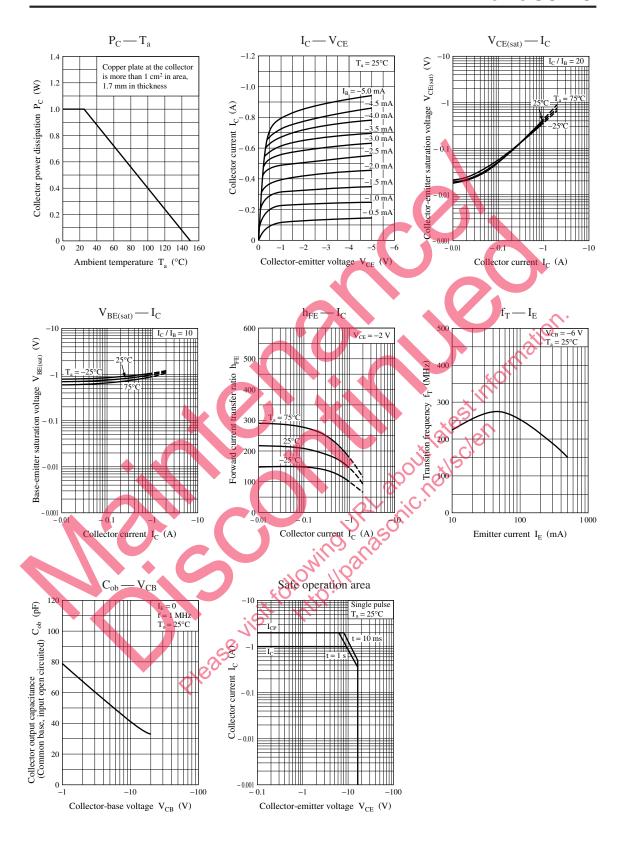
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	$V_{CEO}$	$I_C = 1 \text{ mA}, I_B = 0$	-20			V
Emiter-base voltage (Collector open)	$V_{\rm EBO}$	$I_E = 10  \mu A$ , $I_C = 0$	-5			V
Collector-base cutoff current (Emitter open)	I <sub>CBO</sub>	$V_{CB} = -10 \text{ V}, I_E = 0$			-1	μΑ
Forward current transfer ratio *1	h <sub>FE1</sub>	$V_{CE} = -2 \text{ V}, I_{C} = -500 \text{ mA}$	130		280	_
	ch <sub>FE2</sub>	$V_{CE} = -2 \text{ V}, I_{C} = -1.5 \text{ A}$	50			
Collector-emitter saturation voltage *	V <sub>CE(sat)</sub>	$I_C = -1 \text{ A}, I_B = -50 \text{ mA}$			- 0.5	V
Base-emitter saturation voltage *	V <sub>BE(sat)</sub>	$I_C = -500 \text{ mA}, I_B = -50 \text{ mA}$			-1.2	V
Transition frequency	$f_T$	$V_{CB} = -6 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		200		MHz
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = -6 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		40		pF
(Common base, input open circuited)						

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

### 2. \*1: Pulse measurement

## \*2: Rank classification

Rank	R	S
h <sub>FE1</sub>	130 to 210	180 to 280



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